

IEEE HIR Thermal
Chapter

Thermal TWG will consider three areas:

- (a) Die level.
- (b) Package integration/SIP/module Level.
- (c) System Level (limited to board level).

Thermal TWG will focus on articulating the following in quantitative and qualitative terms:

- (i) Canonical problems with thermal challenges;
- (ii) Cooling limits for known solutions;
- (iii) Advanced concepts and research.

## Years 1-3 (2019-2021)

- Thermal effort kicked off in 2018.
- ~50 industry & university experts
- 2019-2022 chapters published
- Past focus
  - Canonical industry problems
  - Research advances

## 2022 focus

- Quantum Computing cooling
- Advanced thermal modeling
- Immersion cooling
- Stacked die thermal enhancements
- Back side power delivery
- Transient thermals in die
- Silicon micro-channels mfg
- Summary of world's top supercomputer cooling







## New additions in 2022 Chapter (published)

- Emerging challenges and opportunities on thermal modeling for advanced 3D IC system
- Challenges and characterization of hotspots modeling
- Thermal modeling on the High Bandwidth Memory (HBM)
- Thermal challenges related to the integrated voltage regulators (IVR)
- Advanced Liquid Cooling for next Generation data center integrated circuits
- Innovative method for manufacturing silicon microchannel



## *Emerging challenges and opportunities on thermal modeling and simulation for advanced 3DIC system*



Challenges and opportunities on thermal modeling and simulation for advanced 3DIC systems:

- Performing fine-grained static and transient thermal analysis on large 3DIC designs is required and demand adaptive meshing or machinelearning technology to overcome the limitation using traditional CFD/FEA based solvers.
- Architecture-level thermal and thermal-induced stress analysis are required due to the thermal coupling from cross-die horizontally and vertically with transient-based power profile among chiplets in 3DIC.
- Heterogeneous Integration 3DICs may consist of analog/mixed-signal and digital designs which have very different thermal and stress requirements that need to be co-optimized among chiplets and package in 3DIC.
- For Silicon Photonics 3DICs, accurate thermal gradient analysis is required for the co-optimization of 3DIC package and required thermal heater for PIC design.
- Testing of large 3DIC consisting of CPU/GPUs, etc. presents a major challenge due to multiple localized thermal hotspots and dynamic voltage drop affecting yield. Co-optimization of test techniques and localized thermal hotspots and Vdroop on 3DIC should be considered.







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